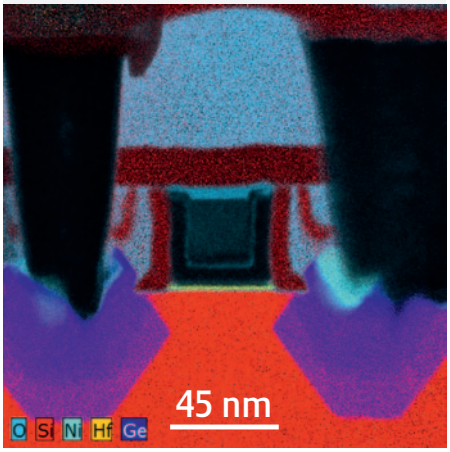
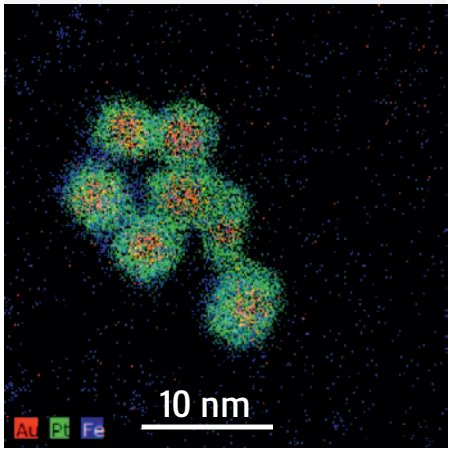
ChemiSTEM™ technology
A revolution in EDX analytics

Large map, all elements



45 nm PMOS structure
600 x 600 pixels
Drift correction applied

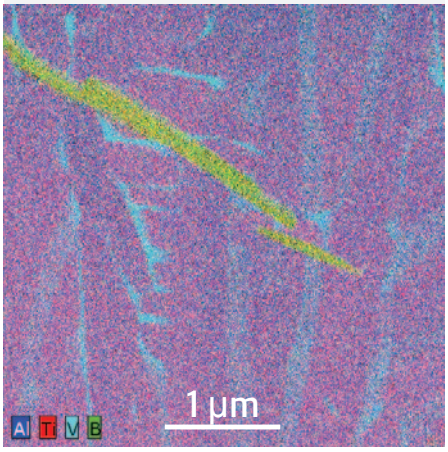
High sensitivity



Au/Pt(Fe) core/shell particles < 5 nm
300 x 300 pixels recorded in < 4 min

Sample courtesy of C. Wang, V. Stamenkovic, N. Markovic and N.J. Zaluzec, Argonne National Laboratory

Light element detection



Boron distribution in TiB/TiAl
512 x 512 pixels recorded in < 5 min
100 µsec dwell time; multiple frames

Sample courtesy of Ohio State University

Tecnai Osiris™

ChemiSTEM™ technology, higher beam current and revolutionary X-ray detection capability:

- **Largest solid angle for EDX detection: 0.9 sr**
- **Ultimate speed: elemental maps in minutes**
- **Highest sensitivity for light elements and low concentrations**

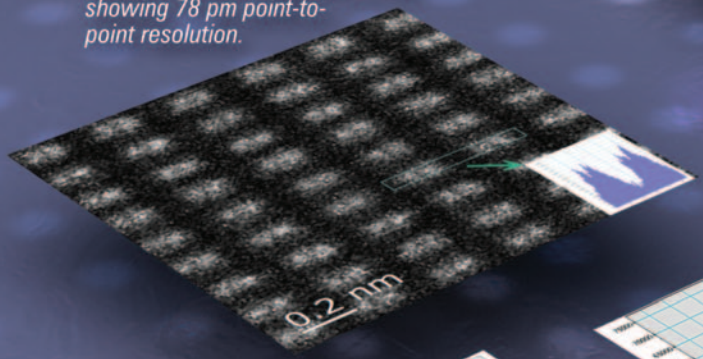
Learn more at FEI.com/research

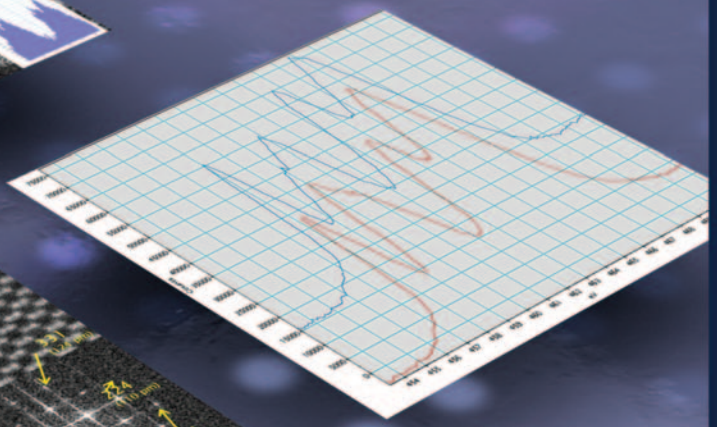
FEI™

Unrivaled Raw Data
You Can Believe.

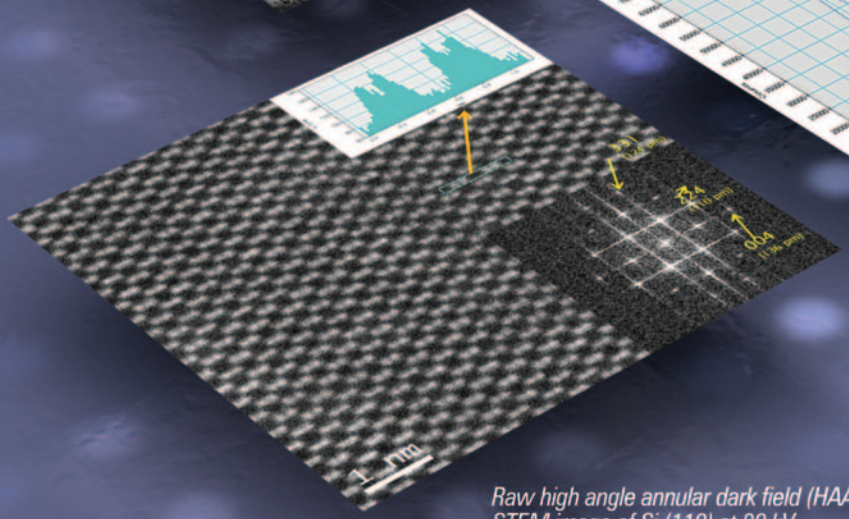
Cold FEG* S/TEM sets a new benchmark for aberration-corrected imaging and chemical mapping.

Raw high angle annular darkfield (HAADF) STEM image of Si (112) showing 78 pm point-to-point resolution.



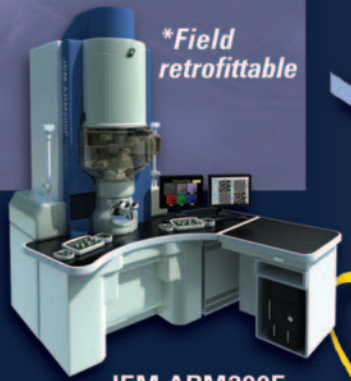


EELS spectra of rutile and anatase TiO_2 showing fine structure differences in the Ti-$L_{2,3}$ edge made visible by the low energy spread of Cold FEG.



Raw high angle annular dark field (HAADF) STEM image of Si (110) at 80 kV.

Contact us for a demo and the raw data is yours!



****Field retrofittable***

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Cold Atomic Resolution S/TEM

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